

INTERNATIONAL STANDARD

NORME INTERNATIONALE

BASIC EMC PUBLICATION
PUBLICATION FONDAMENTALE EN CEM

**Electromagnetic compatibility (EMC) –
Part 4-4: Testing and measurement techniques – Electrical fast transient/burst
immunity test**

**Compatibilité électromagnétique (CEM) –
Partie 4-4: Techniques d'essai et de mesure – Essais d'immunité aux transitoires
électriques rapides en salves**

IEC 61000-4-4:2004

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CONTENTS

FOREWORD.....	4
INTRODUCTION.....	6
1 Scope	7
2 Normative references	7
3 Terms and definitions	8
4 General.....	10
5 Test levels.....	10
6 Test equipment.....	10
6.1 Burst generator	11
6.2 Coupling/decoupling network for a.c./d.c. mains supply port	12
6.3 Capacitive coupling clamp	14
7 Test set-up.....	14
7.1 Test equipment.....	15
7.2 Test set-up for type tests performed in laboratories	15
7.3 Test set-up for post-installation tests.....	17
8 Test procedure	18
8.1 Laboratory reference conditions	18
8.2 Execution of the test	19
9 Evaluation of test results	19
10 Test report	20
Annex A (informative) Information on the electrical fast transients	28
Annex B (informative) Selection of the test levels.....	30
Bibliography	63
Figure 1 – Simplified circuit diagram of a fast transient/burst generator	21
Figure 2 – General graph of a fast transient/burst	21
Figure 3 – Waveshape of a single pulse into a 50 Ω load	22
Figure 4 – Coupling/decoupling network for a.c./d.c. power mains supply ports/terminals.....	22
Figure 5 – Construction of the capacitive coupling clamp	23
Figure 6 – Block diagram for electrical fast transient/burst immunity test	23
Figure 7 – General test set-up for laboratory type tests.....	24
Figure 8 – Example of a test set-up for rack mounted equipment	24
Figure 9 – Example of a test set-up for direct coupling of the test voltage to a a.c./d.c. power supply ports/terminal for laboratory purposes	25
Figure 10 – Example of test set-up for application of the test voltage by the capacitive coupling clamp for laboratory test purposes.....	25

Figure 11 – Example for post-installation test on a.c./d.c. power supply ports and protective earth terminals for stationary, floor-mounted EUT	26
Figure 12 – Example for post-installation test on a.c. mains supply port and protective earth terminals for non-stationary mounted EUT	27
Figure 13 – Example of post-installation test on communications and I/O ports without the capacitive coupling clamp	27
Figure 14 – Verification of the waveform at the common mode output of the coupling/decoupling network	13
Table 1 – Test levels.....	10
Table 2 – Output voltage peak values and repetition rates	12

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ELECTROMAGNETIC COMPATIBILITY (EMC) –**Part 4-4: Testing and measurement techniques –
Electrical fast transient/burst immunity test**

FOREWORD

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International Standard IEC 61000-4-4 has been prepared by sub-committee 77B: High frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

It forms Part 4-4 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107, *Electromagnetic compatibility – Guide to the drafting of electromagnetic compatibility publications*.

This second edition cancels and replaces the first edition published in 1995 and its amendments 1 (2000) and 2 (2001) and constitutes a technical revision.

This second edition improves and clarifies simulator specifications, test criteria and test set-ups. Only common mode injection is required.

The text of this standard is based on the following documents:

FDIS	Report on voting
77B/419/FDIS	77B/424/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

The contents of the corrigendum of August 2006 and June 2007 have been included in this copy.

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WITHDRAWN

INTRODUCTION

IEC 61000 is published in separate parts, according to the following structure:

Part 1: General

- General considerations (introduction, fundamental principles)
- Definitions, terminology

Part 2: Environment

- Description of the environment
- Classification of the environment
- Compatibility levels

Part 3: Limits

- Emission limits
- Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

- Measurement techniques
- Testing techniques

Part 5: Installation and mitigation guidelines

- Installation guidelines
- Mitigation methods and devices

Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: 61000-6-1).

This part is an international standard which gives immunity requirements and test procedures related to electrical fast transients/bursts.

ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-4: Testing and measurement techniques –

Electrical fast transient/burst immunity test

1 Scope

This part of IEC 61000-4 relates to the immunity of electrical and electronic equipment to repetitive electrical fast transients. It gives immunity requirements and test procedures related to electrical fast transients/bursts. It additionally defines ranges of test levels and establishes test procedures.

The object of this standard is to establish a common and reproducible reference for evaluating the immunity of electrical and electronic equipment when subjected to electrical fast transient/bursts on supply, signal, control and earth ports. The test method documented in this part of IEC 61000-4 describes a consistent method to assess the immunity of an equipment or system against a defined phenomenon.

NOTE As described in IEC Guide 107, this is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and if applied, they are responsible for determining the appropriate test levels and performance criteria. TC 77 and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular immunity tests for their products.

The standard defines:

- test voltage waveform;
- range of test levels;
- test equipment;
- verification procedures of test equipment;
- test set-up;
- test procedure.

The standard gives specifications for laboratory and post-installation tests.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161:1990, *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility*

3 Terms and definitions

For the purposes of this document, the following terms and definitions, together with those in IEC 60050-161 apply.

NOTE Several of the most relevant terms and definitions from IEC 60050-161 are presented among the definitions below.

3.1

burst

sequence of a limited number of distinct pulses or an oscillation of limited duration

[IEV 161-02-07]

3.2

calibration

set of operations which establishes, by reference to standards, the relationship which exists, under specified conditions, between an indication and a result of a measurement

NOTE 1 This term is based on the "uncertainty" approach.

NOTE 2 The relationship between the indications and the results of measurement can be expressed, in principle, by a calibration diagram.

[IEV 311-01-09]

3.3

coupling

interaction between circuits, transferring energy from one circuit to another

3.4

common mode (coupling)

simultaneous coupling to all lines versus the ground reference plane

3.5

coupling clamp

device of defined dimensions and characteristics for common mode coupling of the disturbance signal to the circuit under test without any galvanic connection to it

3.6

coupling network

electrical circuit for the purpose of transferring energy from one circuit to another

3.7

decoupling network

electrical circuit for the purpose of preventing EFT voltage applied to the EUT from affecting other devices, equipment or systems which are not under test

3.8

degradation (of performance)

undesired departure in the operational performance of any device, equipment or system from its intended performance

NOTE The term "degradation" can apply to temporary or permanent failure.

[IEV 161-01-19]

3.9**EFT/B**

electrical fast transient/burst

3.10**electromagnetic compatibility (EMC)**

ability of an equipment or system to function satisfactorily in its electromagnetic environment without introducing intolerable electromagnetic disturbances to anything in that environment

[IEV 161-01-07]

3.11**EUT**

equipment under test

3.12**ground reference plane**

flat conductive surface whose potential is used as a common reference

[IEV 161-04-36]

3.13**immunity (to a disturbance)**

ability of a device, equipment or system to perform without degradation in the presence of an electromagnetic disturbance

[IEV 161-01-20]

3.14**port**

particular interface of the EUT with the external electromagnetic environment

3.15**rise time**

interval of time between the instants at which the instantaneous value of a pulse first reaches 10 % value and then the 90 % value

[IEV 161-02-05, modified]

3.16**transient**

pertaining to or designating a phenomenon or a quantity which varies between two consecutive steady states during a time interval which is short compared with the time-scale of interest

[IEV 161-02-01]

3.17**verification**

set of operations which is used to check the test equipment system (e.g. the test generator and the interconnecting cables) and to demonstrate that the test system is functioning within the specifications given in Clause 6

NOTE 1 The methods used for verification may be different from those used for calibration.

NOTE 2 The procedure of 6.1.2 and 6.2.2 is meant as a guide to insure the correct operation of the test generator, and other items making up the test set-up so that the intended waveform is delivered to the EUT.

NOTE 3 For the purpose of this basic EMC standard this definition is different from the definition given in IEC 311-01-13.

4 General

The repetitive fast transient test is a test with bursts consisting of a number of fast transients, coupled into power supply, control, signal and earth ports of electrical and electronic equipment. Significant for the test are the high amplitude, the short rise time, the high repetition rate, and the low energy of the transients.

The test is intended to demonstrate the immunity of electrical and electronic equipment when subjected to types of transient disturbances such as those originating from switching transients (interruption of inductive loads, relay contact bounce, etc.).

5 Test levels

The preferred test levels for the electrical fast transient test, applicable to power, ground, signal and control ports of the equipment are given in Table 1.

Table 1 – Test levels

Open circuit output test voltage and repetition rate of the impulses				
Level	On power port, PE		On I/O (input/output) signal, data and control ports	
	Voltage peak kV	Repetition rate kHz	Voltage peak kV	Repetition rate kHz
1	0,5	5 or 100	0,25	5 or 100
2	1	5 or 100	0,5	5 or 100
3	2	5 or 100	1	5 or 100
4	4	5 or 100	2	5 or 100
X ^a	Special	Special	Special	Special

NOTE 1 Use of 5 kHz repetition rates is traditional; however, 100 kHz is closer to reality. Product committees should determine which frequencies are relevant for specific products or product types.

NOTE 2 With some products, there may be no clear distinction between power ports and I/O ports, in which case it is up to product committees to make this determination for test purposes.

^a "X" is an open level. The level has to be specified in the dedicated equipment specification.

These open-circuit output voltages will be displayed on the EFT/B generator. For selection of levels, see Annex B.

6 Test equipment

The verification procedures of 6.1.2 and 6.2.2 are meant as a guide to insure the correct operation of the test generator, coupling/decoupling networks, and other items making up the test set-up so that the intended waveform is delivered to the EUT.

6.1 Burst generator

The simplified circuit diagram of the generator is given in Figure 1. The circuit elements C_c , R_s , R_m , and C_d are selected so that the generator delivers a fast transient under open circuit conditions and with a $50\ \Omega$ resistive load. The effective output impedance of the generator shall be $50\ \Omega$.

The major elements of the test generator are:

- high-voltage source;
- charging resistor;
- energy storage capacitor;
- high voltage switch;
- impulse duration shaping resistor;
- impedance matching resistor;
- d.c. blocking capacitor.

6.1.1 Characteristics of the fast transient/burst generator

The characteristics of the fast transient/burst generator are the following:

- Output voltage range with $1\ 000\ \Omega$ load shall be at least $0,25\ \text{kV}$ to $4\ \text{kV}$
- Output voltage range with $50\ \Omega$ load shall be at least $0,125\ \text{kV}$ to $2\ \text{kV}$

The generator shall be capable of operating under short-circuit conditions.

Characteristics:

- polarity: positive/negative
- output type: coaxial, $50\ \Omega$
- d.c. blocking capacitor: $10\ \text{nF} \pm 20\ \%$
- repetition frequency: (see Table 2) $\pm 20\ \%$
- relation to power supply: asynchronous
- burst duration: $15\ \text{ms} \pm 20\ \%$ at $5\ \text{kHz}$
(see Figure 2) $0,75\ \text{ms} \pm 20\ \%$ at $100\ \text{kHz}$
- burst period: $300\ \text{ms} \pm 20\ \%$
(see Figure 2)
- wave shape of the pulse
 - into $50\ \Omega$ load
 - rise time $t_r = 5\ \text{ns} \pm 30\ \%$
 - duration t_d (to 50 %) = $50\ \text{ns} \pm 30\ \%$
 - peak voltage = according to Table 2, $\pm 10\ \%$
 - (see Figure 3 for the $50\ \Omega$ waveshape)
 - into $1\ 000\ \Omega$ load
 - rise time $t_r = 5\ \text{ns} \pm 30\ \%$
 - duration t_d (to 50 %) = $50\ \text{ns}$ with a tolerance of $-15\ \text{ns}$ to $+100\ \text{ns}$
 - peak voltage = according to Table 2, $\pm 20\ \%$
 - (see Note 2 below Table 2)

- test load impedance 50 Ω ± 2 %
1 000 Ω ± 2 % in parallel with ≤ 6 pF. The resistance measurement is made at d.c. and the capacitance measurement is made using a commercially available capacitance meter that operates at low frequencies.

6.1.2 Verification of the characteristics of the fast transient/burst generator

The test generator characteristics shall be verified in order to establish a common reference for all generators. For this purpose, the following procedure shall be undertaken.

The test generator output shall be connected to a 50 Ω and 1 000 Ω coaxial termination respectively and the voltage monitored with an oscilloscope. The -3 dB bandwidth of the measuring equipment and the test load impedance shall be at least 400 MHz. The test load impedance at 1 000 Ω is likely to become a complex network. The rise time, impulse duration and repetition rate of the impulses within one burst shall be monitored as well as the burst duration and burst period.

For each of the set voltages of Table 2, measure the output voltage at a 50 Ω load [$V_p(50 \Omega)$]. This measured voltage shall be $[0,5 \times V_p(\text{open circuit})] \pm 10\%$.

With the same generator setting (set voltage), measure the voltage at a 1 000 Ω load - [$V_p(1\ 000 \Omega)$]. This measured voltage shall be $V_p(\text{open circuit}) \pm 20\%$.

NOTE 1 Measures should be taken to ensure that stray capacitance is kept to a minimum.

Table 2 – Output voltage peak values and repetition rates

Set voltage kV	V_p (open circuit) kV	V_p (1 000 Ω) kV	V_p (50 Ω) kV	Repetition frequency kHz
0,25	0,25	0,24	0,125	5 or 100
0,5	0,5	0,48	0,25	5 or 100
1	1	0,95	0,5	5 or 100
2	2	1,9	1	5 or 100
4	4	3,8	2	5 or 100

NOTE 2 Use of a 1 000 Ω load resistor will automatically result in a voltage reading that is 5 % lower than the set voltage as shown in column $V_p(1\ 000 \Omega)$. The reading V_p at 1000 Ω = $V_p(\text{open circuit})$ multiplied times 1000/1050 (the ratio of the test load to the total circuit impedance of 1000 Ω plus 50 Ω).

NOTE 3 With the 50 Ω load, the measured output voltage is 0,5 times the value of the unloaded voltage as reflected in the table above.

6.2 Coupling/decoupling network for a.c./d.c. mains supply port

The coupling/decoupling network is required for acceptance tests of a.c./d.c. power supply ports.